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Applications of Embedded - FPGAs

The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications.

Details	
Product Status	Obsolete
Number of LABs/CLBs	4548
Number of Logic Elements/Cells	90960
Total RAM Bits	4520448
Number of I/O	558
Number of Gates	-
Voltage - Supply	1.15V ~ 1.25V
Mounting Type	Surface Mount
Operating Temperature	0°C ~ 85°C (TJ)
Package / Case	1152-BBGA
Supplier Device Package	1152-FBGA (35x35)
Purchase URL	https://www.e-xfl.com/product-detail/intel/ep2sgx90ef1152c5n

Transmitter Phase Compensation FIFO Buffer

The transmitter phase compensation FIFO buffer resides in the transceiver block at the PCS/FPGA boundary and cannot be bypassed. This FIFO buffer compensates for phase differences between the transmitter PLL clock and the clock from the PLD. After the transmitter PLL has locked to the frequency and phase of the reference clock, the transmitter FIFO buffer must be reset to initialize the read and write pointers. After FIFO pointer initialization, the PLL must remain phase locked to the reference clock.

Byte Serializer

The FPGA and transceiver block must maintain the same throughput. If the FPGA interface cannot meet the timing margin to support the throughput of the transceiver, the byte serializer is used on the transmitter and the byte deserializer is used on the receiver.

The byte serializer takes words from the FPGA interface and converts them into smaller words for use in the transceiver. The transmit data path after the byte serializer is 8, 10, 16, or 20 bits. Refer to Table 2–3 for the transmitter data with the byte serializer enabled. The byte serializer can be bypassed when the data width is 8, 10, 16, or 20 bits at the FPGA interface.

Table 2–3. Transmitter Data with the Byte Serializer Enabled

Input Data Width	Output Data Width
16 bits	8 bits
20 bits	10 bits
32 bits	16 bits
40 bits	20 bits

If the byte serializer is disabled, the FPGA transmit data is passed without data width conversion.

Table 2–4 shows the data path configurations for the Stratix II GX device in single-width and double-width modes.

Refer to the section "8B/10B Encoder" on page 2–8 for a description of the single- and double-width modes.

Table 2–4. Data Path Configurations *Note (1)*

Parameter	Single-Width Mode		Double-Width Mode	
	Without Byte Serialization/ Deserialization	With Byte Serialization/ Deserialization	Without Byte Serialization/ Deserialization	With Byte Serialization/ Deserialization
Fabric to PCS data path width (bits)	8 or 10	16 or 20	16 or 20	32 or 40
Data rate range (Gbps)	0.6 to 2.5	0.6 to 3.125	1 to 5.0	1 to 6.375
PCS to PMA data path width (bits)	8 or 10	8 or 10	16 or 20	16 or 20
Byte ordering *(1)*		✓		✓
Data symbol A (MSB)				✓
Data symbol B		✓		✓
Data symbol C			✓	✓
Data symbol D (LSB)	✓	✓	✓	✓

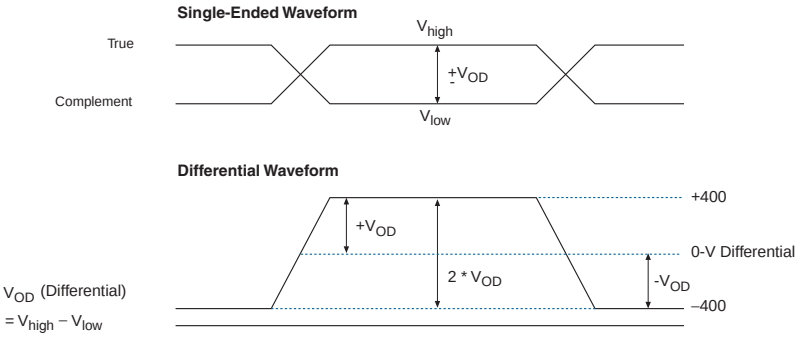
Note to Table 2–4:
(1) Designs can use byte ordering when byte serialization and deserialization are used.

8B/10B Encoder

There are two different modes of operation for 8B/10B encoding. Single-width (8-bit) mode supports natural data rates from 622 Mbps to 3.125 Gbps. Double-width (16-bit cascaded) mode supports data rates above 3.125 Gbps. The encoded data has a maximum run length of five. The 8B/10B encoder can be bypassed. Figure 2–5 diagrams the 10-bit encoding process.

Differential signaling conventions are shown in Figure 2–9. The differential amplitude represents the value of the voltage between the true and complement signals. Peak-to-peak differential voltage is defined as $2 \times (V_{HIGH} - V_{LOW}) = 2 \times$ single-ended voltage swing. The common mode voltage is the average of V_{high} and V_{low}.

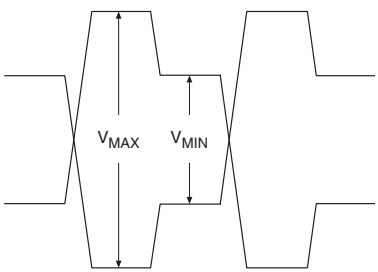
Figure 2–9. Differential Signaling



Programmable Pre-Emphasis

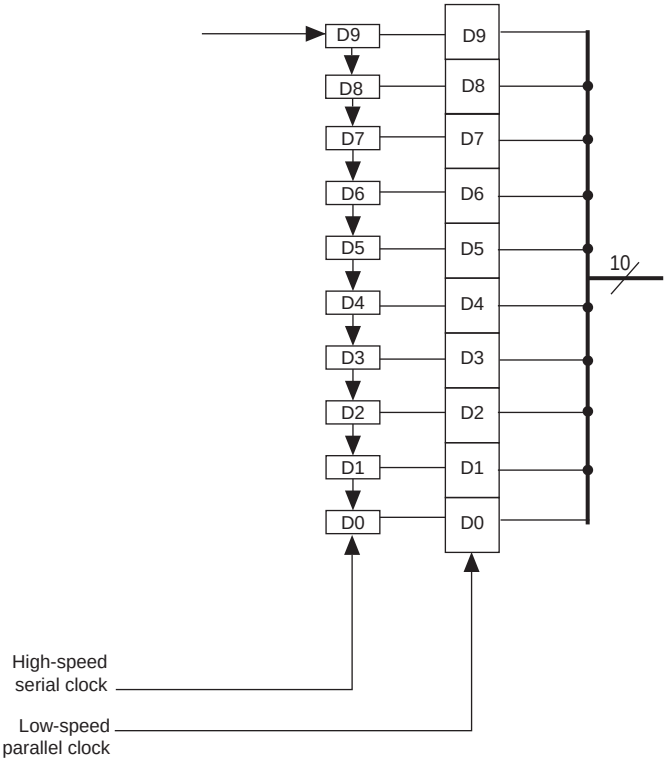
The programmable pre-emphasis module controls the output driver to boost the high frequency components, and compensate for losses in the transmission medium, as shown in Figure 2–10. The pre-emphasis is set statically using the ALT2GXB megafunction or dynamically through the dynamic reconfiguration controller.

Figure 2–10. Pre-Emphasis Signaling



$$\text{Pre-Emphasis \%} = \left(\frac{V_{MAX}}{V_{MIN}} - 1 \right) \times 100$$

Figure 2–17. Deserializer Note (1)

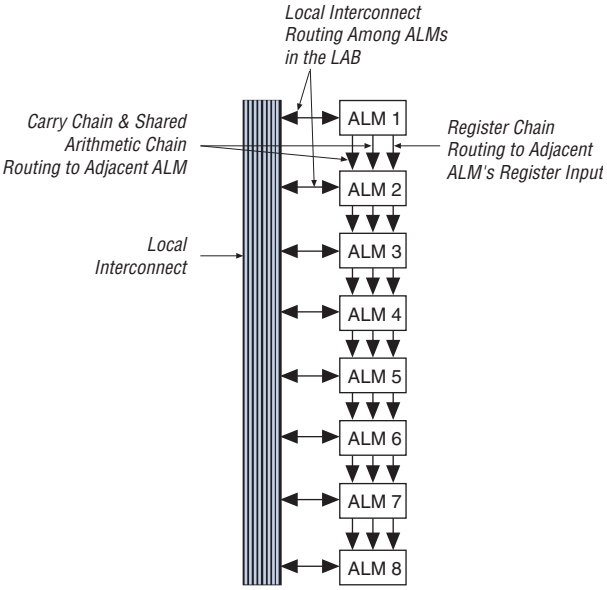


Note to Figure 2–17:
(1) This is a 10-bit deserializer. The deserializer can also convert 8, 16, or 20 bits of data.

Word Aligner

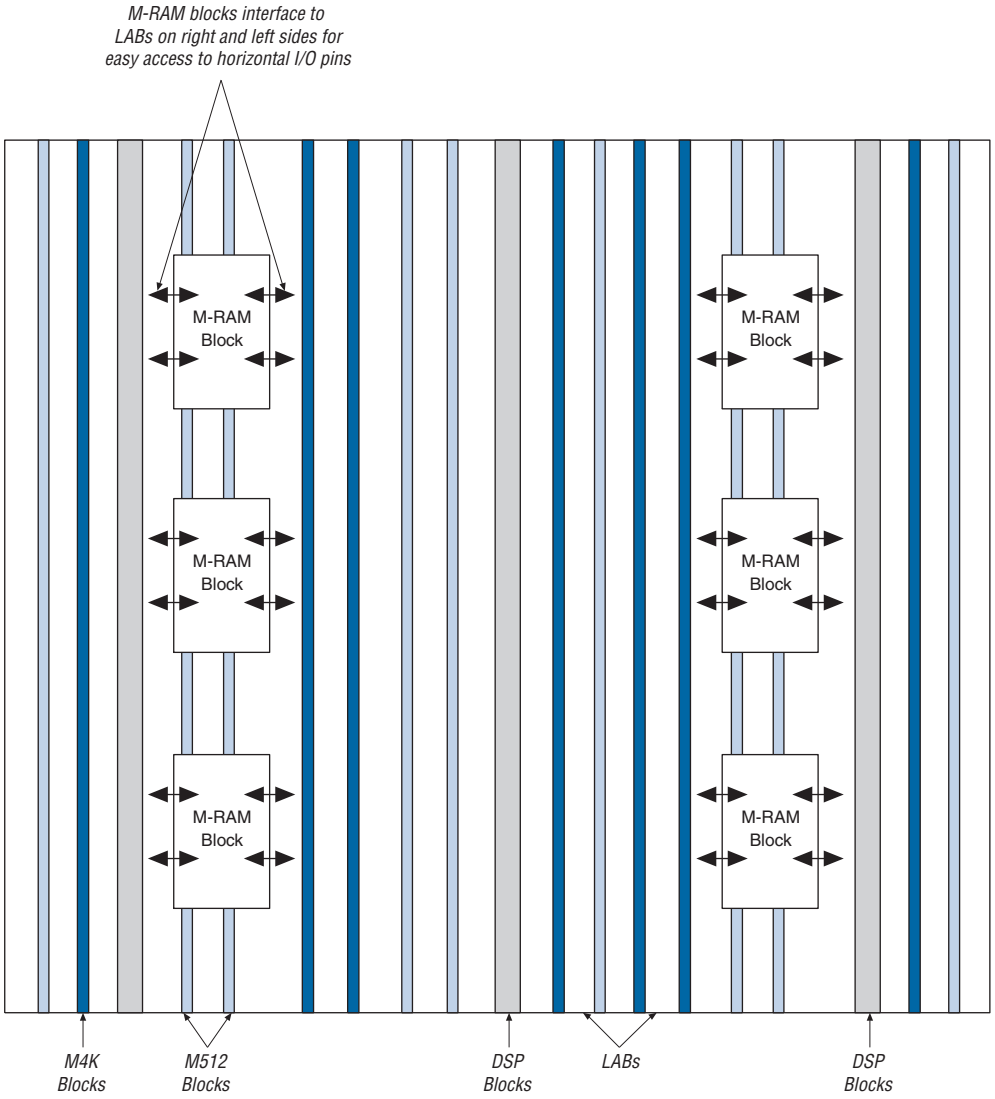
The deserializer block creates 8-, 10-, 16-, or 20-bit parallel data. The deserializer ignores protocol symbol boundaries when converting this data. Therefore, the boundaries of the transferred words are arbitrary. The word aligner aligns the incoming data based on specific byte or word boundaries. The word alignment module is clocked by the local receiver recovered clock during normal operation. All the data and programmed patterns are defined as big-endian (most significant word followed by least significant word). Most-significant-bit-first protocols such as SONET/SDH should reverse the bit order of word align patterns programmed.

Figure 2–47. Shared Arithmetic Chain, Carry Chain and Register Chain Interconnects



The C4 interconnects span four LABs, M512, or M4K blocks up or down from a source LAB. Every LAB has its own set of C4 interconnects to drive either up or down. Figure 2–48 shows the C4 interconnect connections from a LAB in a column. The C4 interconnects can drive and be driven by all types of architecture blocks, including DSP blocks, TriMatrix memory blocks, and column and row IOEs. For LAB interconnection, a primary LAB or its LAB neighbor can drive a given C4 interconnect. C4 interconnects can drive each other to extend their range as well as drive row interconnects for column-to-column connections.

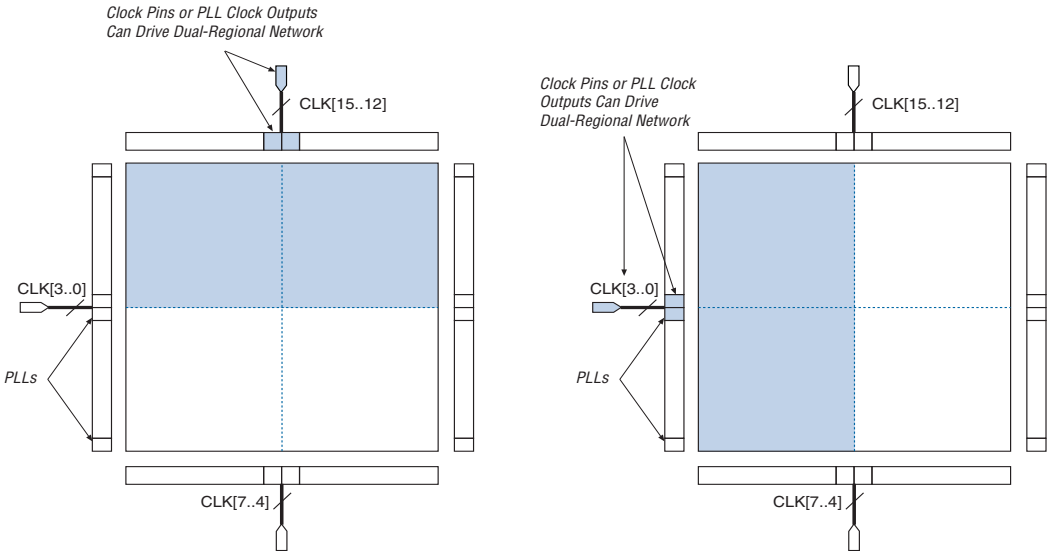
Figure 2–54. EP2SGX130 Device with M-RAM Interface Locations *Note (1)*



Note to Figure 2–54:

(1) The device shown is an EP2SGX130 device. The number and position of M-RAM blocks varies in other devices.

Figure 2–63. Dual-Regional Clocks



Combined Resources

Within each quadrant, there are 24 distinct dedicated clocking resources consisting of 16 global clock lines and 8 regional clock lines. Multiplexers are used with these clocks to form buses to drive LAB row clocks, column IOE clocks, or row IOE clocks. Another multiplexer is used at the LAB level to select three of the six row clocks to feed the ALM registers in the LAB (see Figure 2–64).

Figure 2–64. Hierarchical Clock Networks per Quadrant

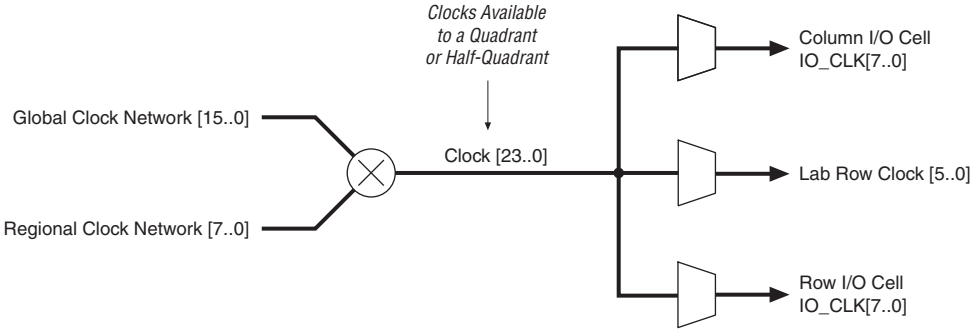
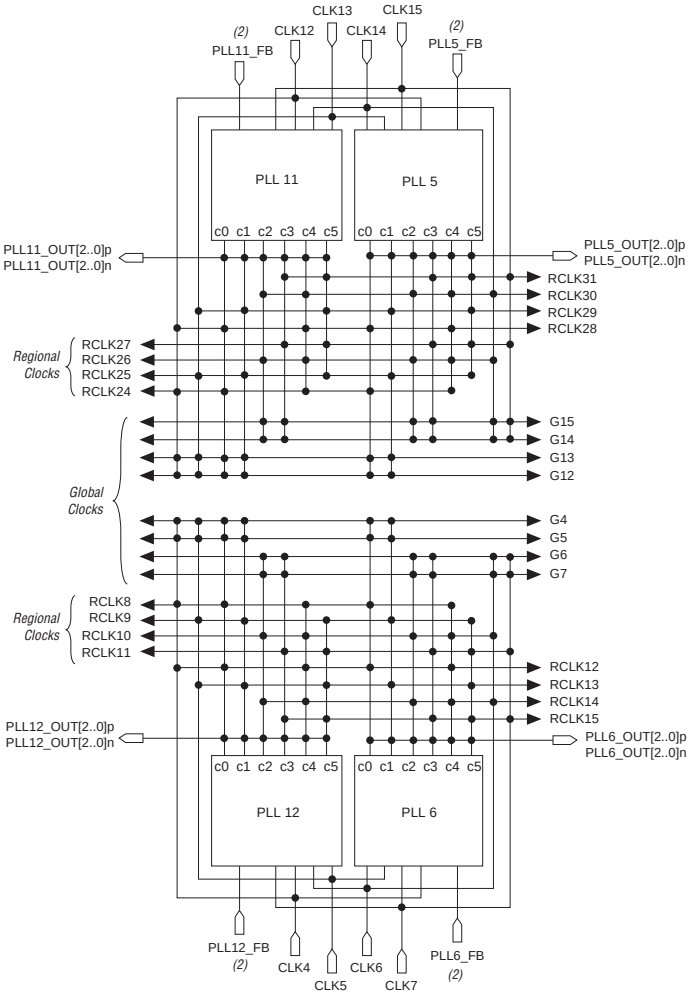


Figure 2–73 shows the global and regional clocking from enhanced PLL outputs and top and bottom CLK pins.

Figure 2–73. Global and Regional Clock Connections from Top and Bottom Clock Pins and Enhanced PLL Outputs *Notes (1), (2)*



Notes to Figure 2–73:

(1) EP2SGX30C/D and EP2SGX60C/D devices only have two enhanced PLLs (5 and 6), but the connectivity from these two PLLs to the global and regional clock networks remains the same as shown.

(2) If the design uses the feedback input, you will lose one (or two, if FBIN is differential) external clock output pin.

The connections to the global and regional clocks from the top clock pins and enhanced PLL outputs are shown in Table 2–28. The connections to the clocks from the bottom clock pins are shown in Table 2–29.

Table 2–28. Global and Regional Clock Connections from Top Clock Pins and Enhanced PLL Outputs (Part 1 of 2)

Top Side Global and Regional Clock Network Connectivity	DLLCLK	CLK12	CLK13	CLK14	CLK15	RCLK24	RCLK25	RCLK26	RCLK27	RCLK28	RCLK29	RCLK30	RCLK31
Clock pins													
CLK12p	✓	✓	✓			✓				✓			
CLK13p	✓	✓	✓				✓				✓		
CLK14p	✓			✓	✓			✓				✓	
CLK15p	✓			✓	✓				✓				✓
CLK12n		✓				✓				✓			
CLK13n			✓				✓				✓		
CLK14n				✓				✓				✓	
CLK15n					✓				✓				✓
Drivers from internal logic													
GCLKDRV0		✓											
GCLKDRV1			✓										
GCLKDRV2				✓									
GCLKDRV3					✓								
RCLKDRV0						✓				✓			
RCLKDRV1							✓				✓		
RCLKDRV2								✓				✓	
RCLKDRV3									✓				✓
RCLKDRV4						✓				✓			
RCLKDRV5							✓				✓		
RCLKDRV6								✓				✓	
RCLKDRV7									✓				✓
Enhanced PLL5 outputs													
c0	✓	✓	✓			✓				✓			
c1	✓	✓	✓				✓				✓		

Table 3–1. Stratix II GX JTAG Instructions

JTAG Instruction	Instruction Code	Description
SAMPLE/PRELOAD	00 0000 0101	Allows a snapshot of signals at the device pins to be captured and examined during normal device operation and permits an initial data pattern to be output at the device pins. Also used by the SignalTap II embedded logic analyzer.
EXTEST *(1)*	00 0000 1111	Allows the external circuitry and board-level interconnects to be tested by forcing a test pattern at the output pins and capturing test results at the input pins.
BYPASS	11 1111 1111	Places the 1-bit bypass register between the TDI and TDO pins, which allows the BST data to pass synchronously through selected devices to adjacent devices during normal device operation.
USERCODE	00 0000 0111	Selects the 32-bit USERCODE register and places it between the TDI and TDO pins, allowing the USERCODE to be serially shifted out of TDO.
IDCODE	00 0000 0110	Selects the IDCODE register and places it between TDI and TDO, allowing the IDCODE to be serially shifted out of TDO.
HIGHZ *(1)*	00 0000 1011	Places the 1-bit bypass register between the TDI and TDO pins, which allows the BST data to pass synchronously through selected devices to adjacent devices during normal device operation, while tri-stating all of the I/O pins.
CLAMP *(1)*	00 0000 1010	Places the 1-bit bypass register between the TDI and TDO pins, which allows the BST data to pass synchronously through selected devices to adjacent devices during normal device operation while holding the I/O pins to a state defined by the data in the boundary-scan register.
ICR instructions		Used when configuring a Stratix II GX device via the JTAG port with a USB-Blaster™, MasterBlaster™, ByteBlasterMV™, or ByteBlaster II download cable, or when using a **.jam** or **.jbc** via an embedded processor or JRunner.
PULSE_NCONFIG	00 0000 0001	Emulates pulsing the nCONFIG pin low to trigger reconfiguration even though the physical pin is unaffected.
CONFIG_IO *(2)*	00 0000 1101	Allows configuration of I/O standards through the JTAG chain for JTAG testing. Can be executed before, during, or after configuration. Stops configuration if executed during configuration. Once issued, the CONFIG_IO instruction holds nSTATUS low to reset the configuration device. nSTATUS is held low until the IOE configuration register is loaded and the TAP controller state machine transitions to the UPDATE_DR state.
SignalTap II instructions		Monitors internal device operation with the SignalTap II embedded logic analyzer.

Notes to Table 3–1:

(1) Bus hold and weak pull-up resistor features override the high-impedance state of HIGHZ, CLAMP, and EXTEST.

(2) For more information on using the CONFIG_IO instruction, refer to the *MorphIO: An I/O Reconfiguration Solution for Altera Devices White Paper.*

The nIO_PULLUP pin is a dedicated input that chooses whether the internal pull-up resistors on the user I/O pins and dual-purpose configuration I/O pins (nCSO, ASDO, DATA[7..0], nWS, nRS, RDYnBSY, nCS, CS, RUnLU, PGM[2..0], CLKUSR, INIT_DONE, DEV_OE, DEV_CLR) are on or off before and during configuration. A logic high (1.5, 1.8, 2.5, 3.3 V) turns off the weak internal pull-up resistors, while a logic low turns them on.

Stratix II GX devices also offer a new power supply, V_{CCPD}, which must be connected to 3.3 V in order to power the 3.3-V/2.5-V buffer available on the configuration input pins and JTAG pins. V_{CCPD} applies to all the JTAG input pins (TCK, TMS, TDI, and TRST) and the following configuration pins: nCONFIG, DCLK (when used as an input), nIO_PULLUP, DATA[7..0], RUnLU, nCE, nWS, nRS, CS, nCS, and CLKUSR. The VCCSEL pin allows the V_{CCIO} setting (of the banks where the configuration inputs reside) to be independent of the voltage required by the configuration inputs. Therefore, when selecting the V_{CCIO} voltage, you do not have to take the V_{IL} and V_{IH} levels driven to the configuration inputs into consideration. The configuration input pins, nCONFIG, DCLK (when used as an input), nIO_PULLUP, RUnLU, nCE, nWS, nRS, CS, nCS, and CLKUSR, have a dual buffer design: a 3.3-V/2.5-V input buffer and a 1.8-V/1.5-V input buffer. The V_{CCSEL} input pin selects which input buffer is used. The 3.3-V/2.5-V input buffer is powered by V_{CCPD}, while the 1.8-V/1.5-V input buffer is powered by V_{CCIO}.

V_{CCSEL} is sampled during power-up. Therefore, the V_{CCSEL} setting cannot change on-the-fly or during a reconfiguration. The V_{CCSEL} input buffer is powered by V_{CCINT} and must be hardwired to V_{CCPD} or ground. A logic high V_{CCSEL} connection selects the 1.8-V/1.5-V input buffer; a logic low selects the 3.3-V/2.5-V input buffer. V_{CCSEL} should be set to comply with the logic levels driven out of the configuration device or the MAX II microprocessor.

If the design must support configuration input voltages of 3.3 V/2.5 V, set V_{CCSEL} to a logic low. You can set the V_{CCIO} voltage of the I/O bank that contains the configuration inputs to any supported voltage. If the design must support configuration input voltages of 1.8 V/1.5 V, set V_{CCSEL} to a logic high and the V_{CCIO} of the bank that contains the configuration inputs to 1.8 V/1.5 V.

For more information on multi-volt support, including information on using TDO and nCEO in multi-volt systems, refer to the *Stratix II GX Architecture* chapter in volume 1 of the *Stratix II GX Device Handbook*.

Table 4–19. Stratix II GX Transceiver Block AC Specification Notes (1), (2), (3) (Part 6 of 19)

Symbol/ Description	Conditions	-3 Speed Commercial Speed Grade			-4 Speed Commercial and Industrial Speed Grade			-5 Speed Commercial Speed Grade			Unit
		Min	Typ	Max	Min	Typ	Max	Min	Typ	Max	
Serial RapidIO Receiver Jitter Tolerance *(11)*											
Deterministic Jitter Tolerance (peak-to-peak)	Data Rate = 1.25, 2.5, 3.125 Gbps REFCLK = 125 MHz Pattern = CJPAT Equalizer Setting = 0 for 1.25 Gbps Equalizer Setting = 6 for 2.5 Gbps Equalizer Setting = 6 for 3.125 Gbps	> 0.37			> 0.37			> 0.37			UI
Combined Deterministic and Random Jitter Tolerance (peak-to-peak)	Data Rate = 1.25, 2.5, 3.125 Gbps REFCLK = 125 MHz Pattern = CJPAT Equalizer Setting = 0 for 1.25 Gbps Equalizer Setting = 6 for 2.5 Gbps Equalizer Setting = 6 for 3.125 Gbps	> 0.55			> 0.55			> 0.55			UI

Table 4–19. Stratix II GX Transceiver Block AC Specification Notes (1), (2), (3) (Part 8 of 19)

Symbol/ Description	Conditions	-3 Speed Commercial Speed Grade			-4 Speed Commercial and Industrial Speed Grade			-5 Speed Commercial Speed Grade			Unit
		Min	Typ	Max	Min	Typ	Max	Min	Typ	Max	
GIGE Transmit Jitter Generation *(12)*											
Deterministic Jitter (peak-to-peak)	Data Rate = 1.25 Gbps REFCLK = 125 MHz Pattern = CRPAT V_{OD} = 1400 mV No Pre-emphasis	-	-	0.14	-	-	0.14	-	-	0.14	UI
Total Jitter (peak-to-peak)	Data Rate = 1.25 Gbps REFCLK = 125 MHz Pattern = CRPAT V_{OD} = 1400 mV No Pre-emphasis	-	-	0.279	-	-	0.279	-	-	0.279	UI
GIGE Receiver Jitter Tolerance *(12)*											
Deterministic Jitter Tolerance (peak-to-peak)	Data Rate = 1.25 Gbps REFCLK = 125 MHz Pattern = CJPAT No Equalization	> 0.4			> 0.4			> 0.4			UI
Combined Deterministic and Random Jitter Tolerance (peak-to-peak)	Data Rate = 1.25 Gbps REFCLK = 125 MHz Pattern = CJPAT No Equalization	> 0.66			> 0.66			> 0.66			UI
HiGig Transmit Jitter Generation *(4), (13)*											
Deterministic Jitter (peak-to-peak)	Data Rate = 3.75 Gbps REFCLK = 187.5 MHz Pattern = CJPAT V_{OD} = 1200 mV No Pre-emphasis	-	-	0.17	-						UI
Total Jitter (peak-to-peak)	Data Rate = 3.75 Gbps REFCLK = 187.5 MHz Pattern = CJPAT V_{OD} = 1200 mV No Pre-emphasis	-	-	0.35	-						UI

Table 4–23. Stratix II GX Device DC Operating Conditions (Part 2 of 2) *Note (1)*

Symbol	Parameter	Conditions	Device	Minimum	Typical	Maximum	Unit
R_{CONF} *(4)*	Value of I/O pin pull-up resistor before and during configuration	Vi = 0, V_{CCIO} = 3.3 V		10	25	50	KOhm
		Vi = 0, V_{CCIO} = 2.5 V		15	35	70	KOhm
		Vi = 0, V_{CCIO} = 1.8 V		30	50	100	KOhm
		Vi = 0, V_{CCIO} = 1.5 V		40	75	150	KOhm
		Vi = 0, V_{CCIO} = 1.2 V		50	90	170	KOhm
	Recommended value of I/O pin external pull-down resistor before and during configuration				1	2	KOhm

Notes to Table 4–23:

(1) Typical values are for T_A = 25 °C, V_{CCINT} = 1.2 V, and V_{CCIO} = 1.5 V, 1.8 V, 2.5 V, and 3.3 V.

(2) This value is specified for normal device operation. The value may vary during power-up. This applies for all V_{CCIO} settings (3.3, 2.5, 1.8, and 1.5 V).

(3) Maximum values depend on the actual TJ and design utilization. See *PowerPlay Early Power Estimator (EPE) and Power Analyzer* or the *Quartus II PowerPlay Power Analyzer and Optimization Technology* (available at **www.altera.com**) for maximum values. See the section "Power Consumption" on page 4–59 for more information.

(4) Pin pull-up resistance values will lower if an external source drives the pin higher than V_{CCIO}.

I/O Standard Specifications

Tables 4–24 through 4–47 show the Stratix II GX device family I/O standard specifications.

Table 4–24. LVTTL Specifications (Part 1 of 2)

Symbol	Parameter	Conditions	Minimum	Maximum	Unit
V_{CCIO} *(1)*	Output supply voltage		3.135	3.465	V
V_{IH}	High-level input voltage		1.7	4.0	V
V_{IL}	Low-level input voltage		–0.3	0.8	V
V_{OH}	High-level output voltage	I_{OH} = –4 mA *(2)*	2.4		V

Table 4–55 shows the Stratix II GX performance for some common designs. All performance values were obtained with the Quartus II software compilation of LPM or MegaCore functions for FIR and FFT designs.

Table 4–55. Stratix II GX Performance Notes (Part 1 of 3) *Note (1)*

Applications		Resources Used			Performance				
		ALUTs	TriMatrix Memory Blocks	DSP Blocks	-3 Speed Grade (2)	-3 Speed Grade (3)	-4 Speed Grade	-5 Speed Grade	Units
LE	16-to-1 multiplexer (4)	21	0	0	657.03	620.73	589.62	477.09	MHz
	32-to-1 multiplexer (4)	38	0	0	534.75	517.33	472.81	369.27	MHz
	16-bit counter	16	0	0	568.18	539.66	507.61	422.47	MHz
	64-bit counter	64	0	0	242.54	231.0	217.77	180.31	MHz
TriMatrix Memory M512 block	Simple dual-port RAM 32 x 18bit	0	1	0	500.0	476.19	447.22	373.13	MHz
	FIFO 32 x 18 bit	22	1	0	500.00	476.19	460.82	373.13	MHz
TriMatrix Memory M4K block	Simple dual-port RAM 128 x 36bit	0	1	0	540.54	515.46	483.09	401.6	MHz
	True dual-port RAM 128 x 18bit	0	1	0	540.54	515.46	483.09	401.6	MHz
	FIFO 128 x 36 bit	22	1	0	524.10	500.25	466.41	381.38	MHz

Table 4–84. Stratix II GX I/O Input Delay for Column Pins (Part 3 of 3)							
I/O Standard	**Parameter**	**Fast Corner Industrial/ Commercial**	**-3 Speed Grade** *(2)*	**-3 Speed Grade** *(3)*	**-4 Speed Grade**	**-5 Speed Grade**	**Unit**
Differential SSTL-2 Class II *(1)*	t_{PI}	530	818	857	912	1094	ps
	t_{PCOUT}	251	382	400	426	511	ps
Differential SSTL-18 Class I *(1)*	t_{PI}	569	898	941	1001	1201	ps
	t_{PCOUT}	290	462	484	515	618	ps
Differential SSTL-18 Class II *(1)*	t_{PI}	569	898	941	1001	1201	ps
	t_{PCOUT}	290	462	484	515	618	ps
1.8-V differential HSTL Class I *(1)*	t_{PI}	569	898	941	1001	1201	ps
	t_{PCOUT}	290	462	484	515	618	ps
1.8-V differential HSTL Class II *(1)*	t_{PI}	569	898	941	1001	1201	ps
	t_{PCOUT}	290	462	484	515	618	ps
1.5-V differential HSTL Class I *(1)*	t_{PI}	587	993	1041	1107	1329	ps
	t_{PCOUT}	308	557	584	621	746	ps
1.5-V differential HSTL Class II *(1)*	t_{PI}	587	993	1041	1107	1329	ps
	t_{PCOUT}	308	557	584	621	746	ps

(1) These I/O standards are only supported on DQS pins.
(2) This column refers to –3 speed grades for EP2SGX30, EP2SGX60, and EP2SGX90 devices.
(3) This column refers to –3 speed grades for EP2SGX130 devices.

Table 4–85. Stratix II GX I/O Input Delay for Row Pins (Part 1 of 3)							
I/O Standard	**Parameter**	**Fast Corner Industrial/ Commercial**	**-3 Speed Grade** *(2)*	**-3 Speed Grade** *(3)*	**-4 Speed Grade**	**-5 Speed Grade**	**Unit**
LVTTL	t_{PI}	749	1287	1350	1435	1723	ps
	t_{PCOUT}	410	760	798	848	1018	ps
2.5 V	t_{PI}	761	1273	1335	1419	1704	ps
	t_{PCOUT}	422	746	783	832	999	ps
1.8 V	t_{PI}	827	1427	1497	1591	1911	ps
	t_{PCOUT}	488	900	945	1004	1206	ps
1.5 V	t_{PI}	830	1498	1571	1671	2006	ps
	t_{PCOUT}	491	971	1019	1084	1301	ps

Table 4–97. Maximum Output Clock Toggle Rate Derating Factors (Part 3 of 5)

I/O Standard	Drive Strength	Maximum Output Clock Toggle Rate Derating Factors (ps/pF)								
		Column I/O Pins			Row I/O Pins			Dedicated Clock Outputs		
		-3	-4	-5	-3	-4	-5	-3	-4	-5
SSTL-18 Class II	8 mA	173	206	206	-	-	-	155	206	206
	16 mA	150	160	160	-	-	-	140	160	160
	18 mA	120	130	130	-	-	-	110	130	130
	20 mA	109	127	127	-	-	-	94	127	127
2.5-V SSTL-2 Class I	8 mA	364	680	680	364	680	680	350	680	680
	12 mA	163	207	207	163	207	207	188	207	207
2.5-V SSTL-2 Class II	16 mA	118	147	147	118	147	147	94	147	147
	20 mA	99	122	122	-	-	-	87	122	122
	24 mA	91	116	116	-	-	-	85	116	116
1.8-V SSTL-18 Class I	4 mA	458	570	570	458	570	570	505	570	570
	6 mA	305	380	380	305	380	380	336	380	380
	8 mA	225	282	282	225	282	282	248	282	282
	10 mA	167	220	220	167	220	220	190	220	220
	12 mA	129	175	175	-	-	-	148	175	175
1.8-V SSTL-18 Class II	8 mA	173	206	206	-	-	-	155	206	206
	16 mA	150	160	160	-	-	-	140	160	160
	18 mA	120	130	130	-	-	-	110	130	130
	20 mA	109	127	127	-	-	-	94	127	127
1.8-V HSTL Class I	4 mA	245	282	282	245	282	282	229	282	282
	6 mA	164	188	188	164	188	188	153	188	188
	8 mA	123	140	140	123	140	140	114	140	140
	10 mA	110	124	124	110	124	124	108	124	124
	12 mA	97	110	110	97	110	110	104	110	110
1.8-V HSTL Class II	16 mA	101	104	104	-	-	-	99	104	104
	18 mA	98	102	102	-	-	-	93	102	102
	20 mA	93	99	99	-	-	-	88	99	99
1.5-V HSTL Class I	4 mA	168	196	196	168	196	196	188	196	196
	6 mA	112	131	131	112	131	131	125	131	131
	8 mA	84	99	99	84	99	99	95	99	99
	10 mA	87	98	98	-	-	-	90	98	98
	12 mA	86	98	98	-	-	-	87	98	98

Table 4–107 shows the high-speed I/O timing specifications for -3 speed grade Stratix II GX devices.

Table 4–107. High-Speed I/O Specifications for -3 Speed Grade *Notes (1), (2)*

Symbol	Conditions			-3 Speed Grade			Unit
				Min	Typ	Max	
$f_{IN} = f_{HSDR} / W$	W = 2 to 32 (LVDS, HyperTransport technology) *(3)*			16		520	MHz
	W = 1 (SERDES bypass, LVDS only)			16		500	MHz
	W = 1 (SERDES used, LVDS only)			150		717	MHz
f_{HSDR} (data rate)	J = 4 to 10 (LVDS, HyperTransport technology)			150		1,040	Mbps
	J = 2 (LVDS, HyperTransport technology)			*(4)*		760	Mbps
	J = 1 (LVDS only)			*(4)*		500	Mbps
$f_{HSDRDPA}$ (DPA data rate)	J = 4 to 10 (LVDS, HyperTransport technology)			150		1,040	Mbps
TCCS	All differential standards			-		200	ps
SW	All differential standards			330		-	ps
Output jitter						190	ps
Output t_{RISE}	All differential I/O standards					160	ps
Output t_{FALL}	All differential I/O standards					180	ps
t_{DUTY}				45	50	55	%
DPA run length						6,400	UI
DPA jitter tolerance *(5)*	Data channel peak-to-peak jitter			0.44			UI
DPA lock time							Number of repetitions
	SPI-4	0000000000 1111111111	10%	256			
	Parallel Rapid I/O	00001111	25%	256			
		10010000	50%	256			
	Miscellaneous	10101010	100%	256			
		01010101		256			

(1) When J = 4 to 10, the SERDES block is used.
(2) When J = 1 or 2, the SERDES block is bypassed.
(3) The input clock frequency and the W factor must satisfy the following fast PLL VCO specification: 150 ≤nput clock frequency × W ≤1,040.
(4) The minimum specification is dependent on the clock source (fast PLL, enhanced PLL, clock pin, and so on) and the clock routing resource (global, regional, or local) utilized. The I/O differential buffer and input register do not have a minimum toggle rate.
(5) For setup details, refer to the characterization report.

Figure 4–14. Stratix II GX JTAG Waveforms.

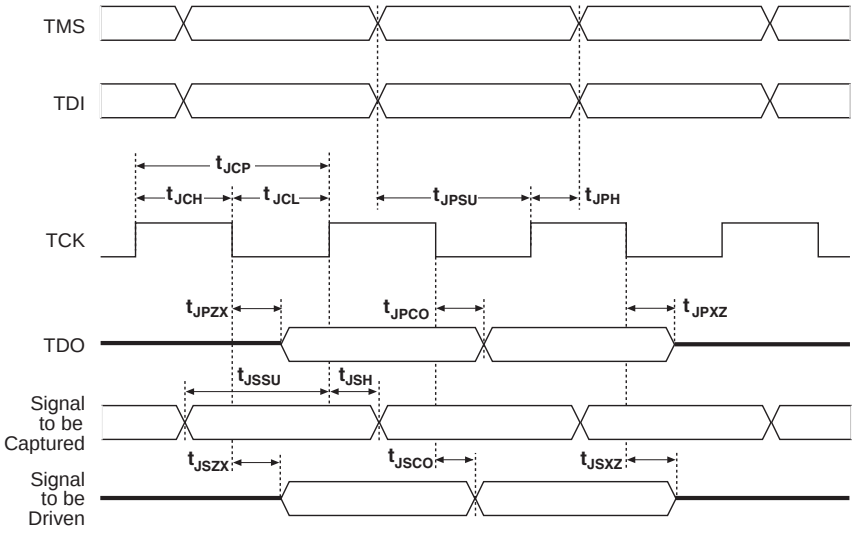


Table 4–117 shows the JTAG timing parameters and values for Stratix II GX devices.

Table 4–117. Stratix II GX JTAG Timing Parameters and Values

Symbol	Parameter	Min	Max	Unit
t_{JCP}	TCK clock period	30		ns
t_{JCH}	TCK clock high time	12		ns
t_{JCL}	TCK clock low time	12		ns
t_{JPSU}	JTAG port setup time	4		ns
t_{JPH}	JTAG port hold time	5		ns
t_{JPCO}	JTAG port clock to output		9	ns
t_{JPZX}	JTAG port high impedance to valid output		9	ns
t_{JPXZ}	JTAG port valid output to high impedance		9	ns
t_{JSSU}	Capture register setup time	4		ns
t_{JSH}	Capture register hold time	5		ns
t_{JSCO}	Update register clock to output		12	ns
t_{JSZX}	Update register high impedance to valid output		12	ns
t_{JSXZ}	Update register valid output to high impedance		12	ns